

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1726	(3D\$1 or three-dimension\$4 or three adj2 dimension\$4 or 3-D\$1)same(assembl\$3)same(compar\$6 or match\$4 or correlat\$6)	US-PGPUB; USPAT	OR	ON	2005/10/20 13:17
L2	387	1 same(measur\$6 or calculat\$4 or comput\$6)	US-PGPUB; USPAT	OR	ON	2005/10/20 13:18
L3	167	2 same(model\$4 or referenc\$4)	US-PGPUB; USPAT	OR	ON	2005/10/20 13:18
L4	54	3 same(sensor\$2 or camera\$2 or scan\$4 or detect\$4)	US-PGPUB; USPAT	OR	ON	2005/10/20 13:19
S1	5735	(artifact\$4 or nois\$4 or distort\$4)same(filter\$3)same(decod\$3)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:26
S2	200	S1 same((spatial\$6 or temporal\$3 or deblock\$3 or dering\$4 or blend\$4)near10 filter\$4)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:43
S3	7388	(artifact\$4 or nois\$4 or distort\$4)same(decod\$3 or cod\$4)same(imag\$3)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:42
S4	820	(artifact\$4 or nois\$4 or distort\$4)same(decod\$3 or cod\$4)same(filter\$3 near10 imag\$3)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:42
S5	144	S4 same((spatial\$6 or temporal\$3 or deblock\$3 or dering\$4 or blend\$4)near10 filter\$4)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:51
S6	325	S4 same((spatial\$6 or temporal\$3 or deblock\$3 or dering\$4 or blend\$4 or block\$4)near10 filter\$4)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:48
S7	15	S6 same(varia\$6 near10 filter\$4)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:51
S8	142	S4 same((spatial\$6 or temporal\$3 or deblock\$3 or dering\$4)near10 filter\$4)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:48
S9	7	S8 same(varia\$6 near10 filter\$4)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:48
S10	1	"6041145".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:49
S11	1	"5949916".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:49
S12	1	"5818964".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:49
S13	1	"5802218".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:49

S14	4490	(artifact\$4 or nois\$4 or distort\$4)same(filter\$3 near10(cod\$4 or decod\$3))	US-PGPUB; USPAT	OR	ON	2005/09/30 15:50
S15	195	S14 same((spatial\$6 or temporal\$3 or deblock\$3 or dering\$4 or blend\$4)near10 filter\$4)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:53
S16	9	S15 same(varia\$6 near10 filter\$4)	US-PGPUB; USPAT	OR	ON	2005/09/30 17:33
S17	124	S14 same(horizontal\$3 or vertical\$3)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:53
S18	4	S17 same(varia\$6 near10 filter\$4)	US-PGPUB; USPAT	OR	ON	2005/09/30 15:53
S19	1	"6178205".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:54
S20	1	"5621468".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:54
S21	1	"5570197".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:54
S22	1	"5512956".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:54
S23	1	"5502510".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:54
S24	1	"5493456".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:55
S25	1	"4991119".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:55
S26	1	"4907082".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:55
S27	1	"5819035".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:55
S28	1	"5374995".PN.	USPAT; USOCR	OR	ON	2005/09/30 15:55
S29	1	"6178205".PN.	USPAT; USOCR	OR	ON	2005/09/30 17:36
S30	1	"5621468".PN.	USPAT; USOCR	OR	ON	2005/09/30 17:37
S31	1	"5570197".PN.	USPAT; USOCR	OR	ON	2005/09/30 17:37
S32	9064	(3D\$1 or three-dimension\$4 or three adj2 dimension\$4 or 3-D\$1)same(assembl\$3 or align\$6 or measur\$6)same(compar\$6 or match\$4 or correlat\$6)	US-PGPUB; USPAT	OR	ON	2005/10/20 13:16
S33	2742	S32 same(model\$3 or referenc\$3)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:42

S34	726	S33 same(assembl\$4 or combin\$6 or merg\$6 or compos\$6)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:37
S35	16884	(3D\$1 or three-dimension\$4 or three adj2 dimension\$4 or 3-D\$1)same(assembl\$3 or align\$6 or measur\$6)same(scan\$4 or read\$4 or captur\$4 or detect\$4)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:36
S36	4136	S35 same(compar\$6 or match\$4 or correlat\$6 or similar\$4)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:37
S37	1180	S36 same(model\$3 or referenc\$3)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:37
S38	356	S37 same(assembl\$4 or combin\$6 or merg\$6 or compos\$6)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:38
S39	444	(3D\$1 or three-dimension\$4 or three adj2 dimension\$4 or 3-D\$1)same(assembl\$3 near10 measur\$6)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:41
S40	106	S39 same(model\$3 or referenc\$3)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:49
S41	29	S39 same(compar\$6 or correlat\$4 or match\$4) near10(measur\$6)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:49
S42	232	S37 same(compar\$6 or correlat\$4 or match\$4) near10(measur\$6)	US-PGPUB; USPAT	OR	ON	2005/10/19 16:04
S43	232	S42 same(model\$3 or referenc\$3)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:50
S44	27	S43 same(auto\$6)	US-PGPUB; USPAT	OR	ON	2005/10/19 15:50
S45	61	S37 same(compar\$6 or correlat\$4 or match\$4) near10(measur\$6 near10(3D\$1 or 3-D\$1 or three-dimension\$4 or three adj2 dimension\$4))	US-PGPUB; USPAT	OR	ON	2005/10/20 13:16
S46	1	"5917937".PN.	USPAT; USOCR	OR	ON	2005/10/19 16:16
S47	1	"5719954".PN.	USPAT; USOCR	OR	ON	2005/10/19 16:18
S48	1	"5582173".PN.	USPAT; USOCR	OR	ON	2005/10/19 16:19
S49	1	"5555352".PN.	USPAT; USOCR	OR	ON	2005/10/19 16:19
S50	1	"5887083".PN.	USPAT; USOCR	OR	ON	2005/10/19 16:20
S51	1	"5845006".PN.	USPAT; USOCR	OR	ON	2005/10/19 16:21
S52	1	"5692061".PN.	USPAT; USOCR	OR	ON	2005/10/19 16:21

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1	(automat\$4 and assess\$4 and measur\$6 and assembl\$4 and three-dimension\$4).clm.	US-PGPUB	OR	ON	2005/10/20 15:48
L2	10	(automat\$4 and assess\$4 and measur\$6 and assembl\$4 and collect\$4).clm.	US-PGPUB	OR	ON	2005/10/20 15:48


[Search Result - Print Format](#)
[< Back](#)

Key: IEEE JNL = IEEE Journal or Magazine, IEEE JNL = IEEE Journal or Magazine, IEEE CNF = IEEE Conference, IEEE CNF = IEEE Conference, IEEE STD = IEEE Standard

1. **Bayesian assembly of 3D axially symmetric shapes from fragments**
 Willis, A.R.; Cooper, D.B.;
 Computer Vision and Pattern Recognition, 2004. CVPR 2004. Proceedings of the 2004 IEEE Computer Society Conference on
 Volume 1, 27 June-2 July 2004 Page(s):I-82 - I-89 Vol.1
 IEEE CNF
2. **Something to smile about: 3D graphics are revolutionizing oral health care**
 Hanson, M.;
 Computer Graphics and Applications, IEEE
 Volume 21, Issue 4, July-Aug. 2001 Page(s):14 - 20
 IEEE JNL
3. **3D computer graphics based interface to real microscopic worlds for μ -robot telemanipulation and position control**
 Sulzmann, A.; Jacot, J.;
 Systems, Man and Cybernetics, 1995. 'Intelligent Systems for the 21st Century', IEEE International Conference on
 Volume 1, 22-25 Oct. 1995 Page(s):286 - 291 vol.1
 IEEE CNF
4. **Test strategies for a 3-D stack multichip module space flight computer**
 Sasidhar, K.; Alkalai, L.; Chatterjee, A.;
 Multichip Modules, 1997., 6th International Conference on
 2-4 April 1997 Page(s):181 - 186
 IEEE CNF
5. **Improvement of metric accuracy of digital 3D models through digital photogrammetry. A case study: Donatello's Maddalena**
 Beraldin, J.-A.; Guidi, G.; Ciofi, S.; Atzeni, C.;
 3D Data Processing Visualization and Transmission, 2002. Proceedings. First International Symposium on
 19-21 June 2002 Page(s):758 - 761
 IEEE CNF
6. **Detection of continuous symmetries in 3D objects from sparse measurements through probabilistic neural networks**
 Chiabert, P.; Costa, M.; Pasero, E.;
 Virtual and Intelligent Measurement Systems, 2001, IEEE International Workshop on. VIMS 2001
 19-20 May 2001 Page(s):104 - 110
 IEEE CNF
7. **Object-based 3D X-ray image reconstruction**
 Benjamin, R.;
 New Developments in 3D Image Capture and Application, IEE Colloquium on
 3 May 1995 Page(s):3/1 - 3/3
 IEEE CNF
8. **Study of eddy currents non destructive testing system in riveted assemblies**
 Rasolonjanahary, J.L.; Thollon, F.; Burais, N.; Brunotte, X.;

Magnetics, IEEE Transactions on
Volume 32, Issue 3, May 1996 Page(s):1585 - 1588
IEEE JNL

9. Experiments in 3D measurements by using single camera and accurate motion

Heimonen, T.; Hannuksela, J.; Heikkila, J.; Leinonen, J.; Manninen, M.;
Assembly and Task Planning, 2001, Proceedings of the IEEE International Symposium on
28-29 May 2001 Page(s):356 - 361

IEEE CNF

10. Fast 3D-surface quality control

Leopold, J.;
Intelligent Processing and Manufacturing of Materials, 1999. IPMM '99. Proceedings of the Second International
Conference on
Volume 1, 10-15 July 1999 Page(s):227 - 232 vol.1

IEEE CNF

11. Probabilistic octree modeling of a 3D dynamic environment

Payeur, P.; Hebert, P.; Laurendeau, D.; Gosselin, C.M.;
Robotics and Automation, 1997. Proceedings., 1997 IEEE International Conference on
Volume 2, 20-25 April 1997 Page(s):1289 - 1296 vol.2

IEEE CNF

12. Use of reduced 3D hexahedral edge elements for 2D TE waveguides and vector potential problems

Bastos, J.P.A.; Ida, N.; Mesquita, R.C.; Gomes, J.;
Magnetics, IEEE Transactions on
Volume 30, Issue 5, Sep 1994 Page(s):3749 - 3752

IEEE JNL

13. Distributed virtual environments

Stytz, M.R.;
Computer Graphics and Applications, IEEE
Volume 16, Issue 3, May 1996 Page(s):19 - 31

IEEE JNL

14. Video representation with three-dimensional entities

Martins, F.C.M.; Moura, J.M.F.;
Selected Areas in Communications, IEEE Journal on
Volume 16, Issue 1, Jan. 1998 Page(s):71 - 85

IEEE JNL

15. VizSim technology helps find oil faster

Delaney, B.;
Computer Graphics and Applications, IEEE
Volume 19, Issue 2, March-April 1999 Page(s):10 - 16

IEEE JNL

16. Estuarine flows measured from an aircraft

Dugan, J.P.; Piotrowski, C.C.;
Current Measurement Technology, 2005. Proceedings of the IEEE/OES Eighth Working Conference on
28-29 June 2005 Page(s):71 - 75

IEEE CNF

17. White light interferometry, a method for optical 3D-inspection of advanced packages

Schaulin, M.; Wolter, K.J.;
Electronics Technology: Meeting the Challenges of Electronics Technology Progress, 2004. 27th International Sprir
Seminar on
Volume 1, 13-16 May 2004 Page(s):42 - 46 vol.1

IEEE CNF

18. Development and characterisation of ultra thin autonomous modules for ambient system applications using 3D packaging techniques

Barton, J.; Majeed, B.; Dwane, K.; Delaney, K.; Bellis, S.; Rodgers, K.; O'Mathuna, S.C.;
Electronic Components and Technology, 2004. ECTC '04. Proceedings
Volume 1, 1-4 June 2004 Page(s):635 - 641 Vol.1

IEEE CNF

19. Machine vision for 3D mechanical part recognition in intelligent manufacturing environments

Yingen Xiong; Quek, F.;
Robot Motion and Control, 2002. RoMoCo '02. Proceedings of the Third International Workshop on
9-11 Nov. 2002 Page(s):441 - 446

IEEE CNF

20. Evolutionary algorithms in kinematic design of robotic systems

Chocron, O.; Bidaud, P.;
Intelligent Robots and Systems, 1997. IROS '97., Proceedings of the 1997 IEEE/RSJ International Conference on
Volume 2, 7-11 Sept. 1997 Page(s):1111 - 1117 vol.2

IEEE CNF

21. A computer-assisted range image registration system for nuclear waste cleanup

Gagnon, E.; Rivest, J.-F.; Greenspan, M.; Burtnyk, N.;
Instrumentation and Measurement Technology Conference, 1996. IMTC-96. Conference Proceedings. 'Quality Measurements: The Indispensable Bridge between Theory and Reality', IEEE
Volume 1, 1996 Page(s):106 - 110 vol.1

IEEE CNF

22. Low frequency PVDF transducers for 3D object profiling in air

Capineri, L.; Fiorillo, A.S.; Rocchi, S.;
Ultrasonics Symposium, 1995. Proceedings., 1995 IEEE
Volume 2, 7-10 Nov. 1995 Page(s):901 - 904 vol.2

IEEE CNF

23. Thermal analysis of power MOSFETs using Rebeca-3D thermal modeling software (from Epsilon Ingenierie) versus physical measurements and possible extractions

Pandya, K.; Jaunay, S.;
Thermal, Mechanical and Multi-Physics Simulation and Experiments in Micro-Electronics and Micro-Systems, 2005. EuroSimE 2005. Proceedings of the 6th International Conference on
18-20 April 2005 Page(s):394 - 397

IEEE CNF

24. Augmented reality with tangible auto-fabricated models for molecular biology applications

Gillet, A.; Sanner, M.; Stoffler, D.; Goodsell, D.; Olson, A.;
Visualization, 2004. IEEE
2004 Page(s):235 - 241

IEEE CNF

25. A new method of measuring the 3-D shape and surface reflectance of an object using a laser rangefinder

Baba, M.; Narita, D.; Ohtani, K.;
Instrumentation and Measurement Technology Conference, 2004. IMTC 04. Proceedings of the 21st IEEE
Volume 2, 18-20 May 2004 Page(s):1349 - 1353 Vol.2

IEEE CNF